

EAST Search History

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|------|-------------------------------------|--|------------------|---------|------------------|
| S1 | 5 | test with pattern and opc and walsh | US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/11/30 09:06 |
| S2 | 18 | pattern and opc and walsh | US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/11/30 09:07 |
| S3 | 13 | S2 not S1 | US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/11/30 09:07 |
| S4 | 865 | pattern same walsh | US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/11/30 09:07 |
| S5 | 865 | pattern same walsh | US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/11/30 09:07 |
| S6 | 3 | pattern same walsh and opc | US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/11/30 09:08 |
| S7 | 122 | opc test pattern layout synthesis | US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB | AND | ON | 2007/11/30 09:30 |
| S8 | 1 | ("6952818").PN. | US-PGPUB; USPAT | OR | OFF | 2007/11/30 09:33 |

EAST Search History

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|-----|------|---|--|-----|-----|------------------|
| S9 | 91 | S7 and "716"/\$.ccls. | US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/11/30 09:30 |
| S10 | 1 | S9 and walsh | US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/11/30 09:30 |
| S11 | 1 | (System method testing pattern sensitive algorithms semiconductor design).ti. | US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB | AND | ON | 2007/11/30 09:53 |
| S12 | 1531 | walsh near4 (transform or matri\$4) | US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB | AND | ON | 2007/11/30 09:53 |
| S13 | 132 | S12 same pattern | US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB | AND | ON | 2007/11/30 13:16 |
| S14 | 1 | ("6446248").PN. | US-PGPUB; USPAT | OR | OFF | 2007/11/30 13:16 |